Am27S181/27S181A Am27S281/27S281A

8,192-Bit (1024x8) Bipolar PROM



DISTINCTIVE CHARACTERISTICS

- · Fast access time allows high system speed
- 50% power savings on deselected parts enhances reliability through total system heat reduction
- Platinum-Silicide fuses guarantee high reliability, fast programming and exceptionally high programming yields (typ > 98%)
- Rapid recovery from power-down state provides minimum delay

GENERAL DESCRIPTION

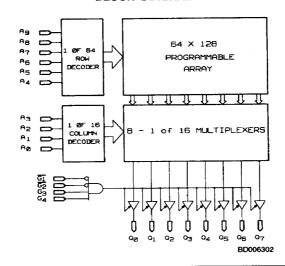
The Am27S181 (1024 words by 8 bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs which are compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic

replacement. Easy word-depth expansion is facilitated by both active LOW $(\overline{G_1} \text{ and } \overline{G_2})$ and active HIGH $(G_3 \text{ and } G_4)$ output enables.

This device is also available in a 300-mil. lateral-center DIP (Am27S281).

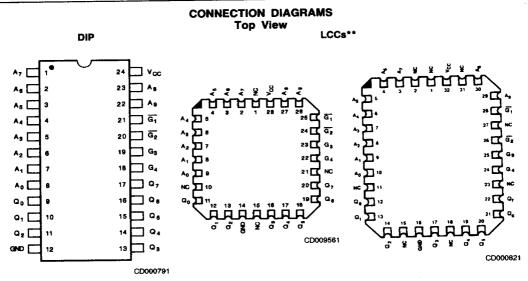
BLOCK DIAGRAM



PRODUCT SELECTOR GUIDE

Three-State Part Number	Am27S181A, Am27S281A		Am275181, Am275281	
Address Access Time	35 ns	50 ns	60 ns	80 ns
Operating Range	С	М	С	м

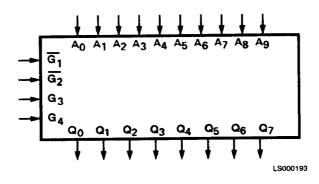
Publication # Rev. Amendment 03182 D /0 Issue Date: Jenuary 1989



^{*}Also available in a 300-mil DIP and a 24-pin Flatpack. Pinout identical to those listed here for the 600-mil DIP.

Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



^{**}Also available in a 28-Pin Square PLCC. Pinout identical to the 28-Pin LCC.

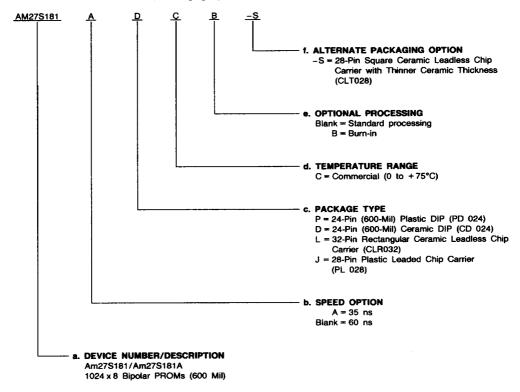
ORDERING INFORMATION

(Am27S181/181A)

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Package Type
- d. Temperature Range
- e. Optional Processing
- f. Alternate Packaging Option



Valid Combinations					
AM27S181	PC, PDB, DC, DCB, LC, LCB, LC-S, LCB-S				
AM27S181A	JC, JCB				

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

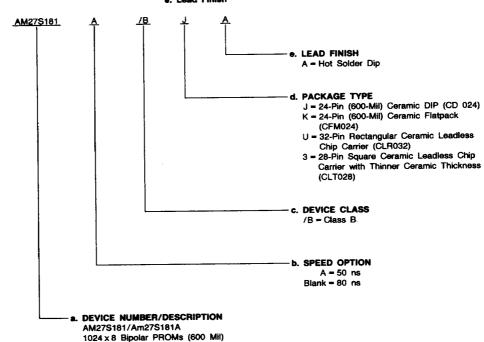
MILITARY ORDERING INFORMATION

(Am27S181/181A)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type
- e. Lead Finish



Valid Combinations					
AM27S181	/BJA, /BKA, /BUA,				
AM27S181A	/B3A				

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

MILITARY BURN-IN

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

5-173

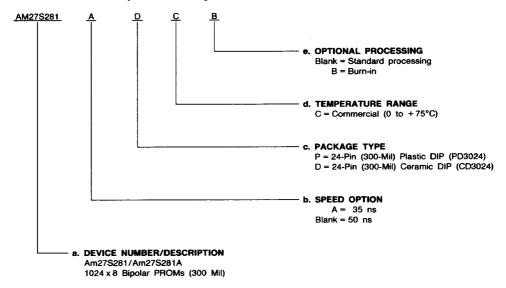
ORDERING INFORMATION

(Am27S281/281A)

Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Package Type
- d. Temperature Range
- e. Optional Processing



Valid Co	embinations
AM27S281	PC. PCB. DC. DCB
AM27S281A	PC, PCB, DC, DCB

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

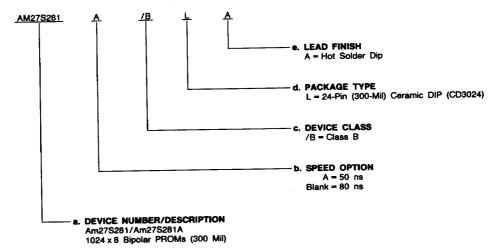
MILITARY ORDERING INFORMATION

(Am27S281/281A)

APL Products

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) for APL products is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type
- e. Lead Finish



Valid C	ombinations	
AM27S281	/BLA	
AM27S281A	785	

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

Group A Tests

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

MILITARY BURN-IN

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Method 1015, Conditions A through E. Test conditions are selected at AMD's option.

PIN DESCRIPTION

A₀ - A₉ Address Inputs

The 10-bit field presented at the address inputs selects one of 1,048 memory locations to be read from.

Q₀ - Q₇ Data Output Port

The outputs whose state represents the data read from the selected memory locations.

G, G₂, G₃, G₄ Output Enable

Provides direct control of the Q output buffers. Outputs disabled force all outputs to a floating or high-impedance

Enable =
$$\overline{G}_1 \cdot \overline{G}_2 \cdot G_3 \cdot G_4$$

Disable =
$$\overline{G}_1 \cdot \overline{G}_2 \cdot G_3 \cdot G_4$$

= $G_1 + G_2 + \overline{G}_3 + \overline{G}_4$

V_{CC} Device Power Supply Pin

The most positive of the logic power supply pins

GND Device Power Supply Pin

The most negative of the logic power supply pins.

5-175

ABSOLUTE MAXIMUM RATINGS

Storage Temperature	65 to +150°C
Ambient Temperature with	
Power Applied	55 to +125°C
Supply Voltage	0.5 V to +7.0 V
DC Voltage Applied to Outputs	
(Except During Programming)	0.5 V to +V _{CC} Max.
DC Voltage Applied to Outputs	
During Programming	21 V
Output Current into Outputs During	
Programming (Max. Duration of 1 se	ec) 250 mA
DC Input Voltage	0.5 V to +5.5 V
DC Input Current	30 mA to +5 mA

Stresses above those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to absolute maximum ratings for extended periods may affect device reliability.

OPERATING RANGES

Commercial (C) Devices	
Ambient Temperature (TA)	0 to +75°C
Supply Voltage (VCC)+4.75 V	
Military (M) Devices*	
Case Temperature (T _C)	to +125°C
Supply Voltage (V _{CC}) +4.5 \	√ to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

*Military product 100% tested at $T_C = +25$ °C, +125°C, and -55°C.

DC CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Parameter Symbol	Parameter Description	Test Condition	ens	Min.	Тур.	Max.	Unkt
VOH	Output HIGH Voltage	V _{CC} = Min., I _{OH} = -2.0 mA V _{IN} = V _{IH} or V _{IL}					V
VOL	Output LOW Voltage	V _{CC} = Min., I _{OL} = 16 mA V _{IN} = V _{IH} or V _{IL}	V _{CC} = Min., I _{OL} = 16 mA			0.50	٧
V _{IH}	Input HIGH Level	Guaranteed input logical HIGH voltage for all inputs (Note 3)		2.0			ν
VIL	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 3)				0.8	٧
IIL	Input LOW Current	V _{CC} = Max., V _{IN} = 0.45 V				-0.250	mA
Ін	Input HIGH Current	V _{CC} = Max., V _{IN} = V _{CC}	V _{CC} = Max., V _{IN} = V _{CC}			40	μΑ
Isc	Output Short-Circuit Current	VCC = Max., VOUT = 0.0 V COM'L		-20		-90	
'SC	Capat Short-Sircal Carrent	(Note 1)	MIL	-15		-90	mA
lcc	Power Supply Current	All Inputs = GND	All Inputs = GND			185	mA
VI	Input Clamp Voltage	V _{CC} = Min., I _{IN} = -18 mA	V _{CC} = Min., I _{IN} = -18 mA			-1.2	٧
ICEX	Output Leakage Current V _{CC} = Max. V _O =	Vo = Voc			40	<u> </u>	
'UEX	Cupul Coarage Culterit	VG1 = 2.4 V	V _O = 0.4 V			-40	μΑ
CIN	Input Capacitance	V _{IN} = 2.0 V @ f = 1 MHz (Note 2) V _{CC} = 5 V, T _A = 25°C V _{OUT} = 2.0 V @ f = 1 MHz (Note 2) V _{CC} = 5 V, T _A = 25°C			4.0		
COUT	Output Capacitance				8.0		рF

Notes: 1. Not more than one output should be shorted at a time. Duration of the short-circuit test should not be more than one second.

2. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where capacitance may be affected.

 Vi_L and Vi_H are input conditions of output tests and are not themselves directly tested. Vi_L and V_{IH} are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.

SWITCHING CHARACTERISTICS (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted*)

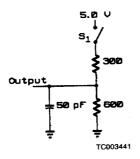
	Parameter	Parameter		COM'L	MIL	İ
No. Symbol	Description	Version	Max.	Max.	Unit	
1	1 TAVQV Address Valid to Output Valid Access Time	A	35	50		
<u> </u>		Access Title	STD	60	80	ns
2	TGVQZ	Delay from Output Enable Valid to Output Hi-Z	. A	25	30	
	TEVQZ		STD	40	50	ns
3	TGVQV	Delay from Output Enable Valid to Output Valid	A	25	30	
-	TEVQV Soldy Hollin Coupet Enable Valid to Coupet Valid	John Coper Enable Valid to Colput Valid	STD	40	50	ns

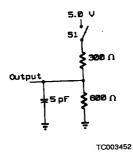
See also Switching Test Circuits.

Notes: 1. Tests are performed with input transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V using test load in Figure A.

 TGVQZ is measured at steady state HIGH output voltage -0.5 V and steady state LOW output voltage +0.5 V output levels using the test load in Figure B.

SWITCHING TEST CIRCUITS



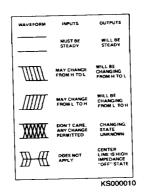


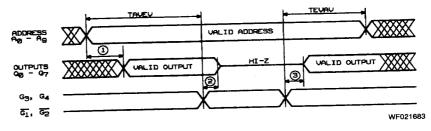
A. Output Load for all Switching tests except **TGVQZ**

B. Output Load for TGVQZ

- Notes: 1. All device test loads should be located within 2" of device output pin.
 - 2. S₁ is open for Output Data HIGH to Hi-Z and Hi-Z to Output Data HIGH tests.
 - S₁ is closed for all other Switching tests.
 - 3. Load capacitance includes all stray and fixture capacitance.

SWITCHING WAVEFORM KEY TO SWITCHING WAVEFORMS





5-177